ISO 20411:2018-03 (E)

Surface chemical analysis - Secondary ion mass spectrometry - Correction method for satura ted intensity in single ion counting dynamic secondary ion mass spectrometry

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Contents

Page

Foreword iv

Introduction v

1 Scope 1

2 Normative references 1

3 Termsanddefinitions 1

4 Symbols and abbreviated terms 2

5 Outline of method 3

6 Procedure for evaluating intensity linearity 5
6.1 Obtaining reference sample 5
6.2 Setting the sample 5
6.3 Operating the instrument 5
6.3.1 Setting the ion beam and the mass analyser 5
6.3.2 Setting the charge compensation 5
6.3.3 Setting the ion detector 5
6.4 Acquiring the data 5
6.5 Assessing the linearity without and with intensity correction 6
6.5.1 Interpolating the minor isotope intensity 6
6.5.2 Correcting the ratio of the isotope abundance to the instrument transmittance 7
6.5.3 Assessing the linearity of intensity 8
6.5.4 Correcting the saturated intensity 8
6.5.5 Assessing the uncertainty of the data 11

7 Reporting the results 12

8 Correcting saturated intensity to the measurement results of the analysis samples 12

Annex A (informative) Effect of the dead time correction with various instruments for VAMAS study 13

Bibliography 15